

Contents

1	XRF-Basics	1
1.1	Introduction	1
1.2	Interaction of X-rays with Matter Used for Material Characterization	3
1.2.1	Absorption	4
1.2.2	Emission of Fluorescence Radiation	6
1.2.3	Refraction	8
1.2.4	Scattering	8
1.2.5	Diffraction	12
1.3	General Design of X-ray Spectrometers	14
	References	15
2	Main Components of X-ray Spectrometers	19
2.1	Excitation Source	19
2.1.1	Excitation by Electrons	19
2.1.2	Excitation by Photons	23
2.1.3	X-ray Tubes	23
2.1.4	Conclusions for Excitation in μ -XRF	33
2.2	Primary Optics	33
2.2.1	Basic Properties of X-ray Optics	34
2.2.2	Diffraction Optics	35
2.2.3	Refraction Optics	43
2.2.4	Reflection Zone Plates	47
2.2.5	Optics Based on Total Reflection	48
2.2.6	Comparison of Different Optics for Their Use in μ -XRF	67
2.3	Sample Positioning and Radiation Shielding	69
2.3.1	Special Requirements for Sample Positioning in μ -XRF	71
2.3.2	Image View	75
2.3.3	Spatial Resolution	76
2.3.4	Measurement Media	82

2.4	Secondary Optics: Spectrometer Type	83
2.4.1	Wavelength Dispersive Spectrometers	83
2.4.2	Energy Dispersive Spectrometers	85
2.5	X-ray Detectors	87
2.5.1	Working Principles and Detector Types	87
2.5.2	Generation of an Energy Dispersive Spectrum	91
2.5.3	Energy Resolution	92
2.5.4	Detection Efficiency	97
2.5.5	Development of Energy Dispersive X-ray Detectors	101
2.5.6	Detector Artifacts	108
	References	115
3	Special Requirements for μ-XRF	119
3.1	History of Position Sensitive Element Analysis	119
3.2	Possibilities for Spatial Resolved XRF	122
3.2.1	Excitation of a Small Sample Area	122
3.2.2	Excitation of a Large Sample Area	123
3.2.3	Confocal Geometry	125
3.3	Instrument Types	126
3.3.1	Spot Generation	127
3.3.2	Excitation Direction	127
3.3.3	Detector Types	128
3.3.4	Measurement Medium	128
3.3.5	Sample Movement	130
3.3.6	Type of the Spectrometer	130
3.3.7	Instruments on the Market	131
3.4	Typical Measurement Modes for μ -XRF	133
3.4.1	Single Point Measurement	133
3.4.2	Mutiple Point Measurement	134
3.4.3	Area Analysis	134
3.4.4	Linescan	135
3.4.5	Mapping	135
	References	154
4	Quantification	157
4.1	Introduction	157
4.2	Different Types of Quantification	160
4.2.1	Qualitative and Semi-quantitative Methods	160
4.2.2	Quantification Methods	160
4.3	Quantification for μ -XRF	163
4.3.1	Special Conditions	163
4.3.2	Quantification with the Fundamental Parameter Model	168
4.3.3	Summary	176

4.4	Analysis of Coating Systems.	176
4.4.1	Principle of Coating Analysis.	176
4.4.2	Requirements for Coating Analysis.	178
4.4.3	General Equations for Coating Thickness Testing.	180
4.4.4	Thickness Ranges for the Coating Measurements.	181
4.4.5	Multiple Layer Analysis.	183
4.4.6	Accuracy for Coating Analysis.	185
4.4.7	Summary.	187
4.5	Errors in μ -XRF.	188
4.5.1	Characterization of Errors.	188
4.5.2	Random Error Contributions.	190
4.5.3	Systematic Error Contributions.	192
4.5.4	Concept of Uncertainty.	193
4.5.5	Possibilities for Improvement of Accuracy.	196
	References.	198
5	Sample Preparation.	201
5.1	Introduction.	201
5.2	Information Depth.	202
5.3	Preparation and Presentation of Different Sample Qualities.	203
5.3.1	Solid Samples.	203
5.3.2	Powder Samples.	206
5.3.3	Filter Materials.	207
5.3.4	Liquid Samples.	207
5.3.5	Archeological Samples.	208
	References.	209
6	Relations to Other Analytical Methods.	211
6.1	Comparison with Other Micro-Analytical Methods.	211
6.1.1	Overview.	211
6.1.2	Synchrotron Excited μ -XRF.	214
6.1.3	SEM-EDS.	214
6.2	Combination of μ -XRF with Other Methods.	220
6.2.1	General Remarks.	220
6.2.2	SEM-EDS and μ -XRF.	221
6.2.3	μ -XRF and μ -XRD.	225
6.2.4	Raman Spectroscopy and μ -XRF.	225
	References.	226
7	Applications.	229
7.1	Point Analysis.	229
7.1.1	Analysis of Precious Metal Alloys.	230
7.1.2	Coating Thickness Analysis.	236
7.1.3	Analysis of Particles and Inclusions.	249
7.1.4	Analysis of Restricted Elements in Consumer Goods.	256

7.2	Multiple Point Analysis	258
7.2.1	Area Analysis.	259
7.2.2	Muliti-point Measurements.	262
7.2.3	High Throughput Screening	262
7.3	One Dimensional Distribution Analysis: LineScan.	268
7.3.1	Determination of Diffusion Profiles.	268
7.3.2	Analysis of Gems	268
7.3.3	Examination of Roll Bearings.	269
7.3.4	Analysis of Sediment Bore Cores	270
7.4	Two Dimensional Distribution Analysis: Mapping.	275
7.4.1	Analysis of Geological Samples	275
7.4.2	Examination of Art Objects	283
7.4.3	Life Science Applications	290
7.4.4	Electronics	295
7.4.5	Material Analysis	298
7.4.6	Forensic Applications	308
7.5	Three Dimensional Distribution Analysis	315
7.5.1	Destructive 3D-Analysis	316
7.5.2	Measurements with Confocal Geometry.	316
	References	336
8	Prospectives for μ-XRF	343
8.1	Instrumentation	343
8.2	Instrument Control and Data Evaluation.	347
	Reference	348
	Further Readings	349
	Index	351

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